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LOW FREQUENCY DIELECTRIC CONSTANTS OF THE ALKALINE EARTH FLUORIDES BY THE METHOD OF SUBSTITUTION

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The 1000 Hz 300[°]K dielectric constants of the alkaline earth fluorides were measured to an accuracy of 0.01% by the method of substitution. Reproducibly different values for various crystals of the same type were obtained which varied beyond the experimental error. The ranges of results for various crystals of each type measured, along with further separation by manufacturer are: CaF₂, Harshaw, 6.7984-6.7988, Optovac, 6.8074-6.8432; SrF₂, Harshaw, 6.4647-6.4664, Optovac, 6.4700-6.4703; and BaF₂, Harshaw, 7.3590-7.3595, Optovac, 7.3606-7.3630. The spread for each type of crystal is thought to be attributable to random trace impurities.

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The Low Frequency Dielectric Constants of the Alkaline Earth Fluorides by the Method of Substitution*

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INTRODUCTION

The alkaline earth fluorides have been extensively studied in recent years. Belonging to the space group 0_h^5 , CaF2, SrF2, and BaF2 are of interest as a set of isomorphic cubic crystals with the fluorite structure. This series is particularly important in that the variation of the physical properties with the alkaline earth cation can be studied. Valuable details of electronic structure are then obtained, and one of the most productive areas of research yielding such information is that concerned with the dielectric properties of ionic crystals. There have been several studies 1-5 and reviews 6,7 dealing with these aspects of the alkaline earth fluorides. From these articles, it becomes apparent that one of the least welldetermined parameters, yet one of the most important, is the static dielectric constant. Past literature values are collected in Table I where it is seen that in general the numbers are randomly scattered with the discrepancies reaching as high as 10%. There is one set of values, those tabulated by Hojendahl⁷ who quotes the results of Errera and Ketelaar, which, for CaF_2 and SrF_2 , are in total disagreement with the values of the other workers. It is unfortunate that these have been the most commonly quoted results, and, for whatever reason, continue to

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This work resolves the discrepancies by establishing highly accurate values of the static dielectric constants of the alkaline earth fluorides by the method of substitution.^{10,11} In addition some information is given on the order of magnitude of the effect of random trace impurities.

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THEORY

The method of substitution has been described previously.^{10,11} The basic idea is to measure five capacitances:

$$C_{1} = \frac{\varepsilon_{S}^{1}}{d} \qquad (1a)$$

: Fluid of static
dielectric constant ε_{S}^{1} ,

$$C_{2} = \frac{\varepsilon_{S}^{1}}{\varepsilon_{S}^{5}} \frac{\varepsilon_{S}^{8}}{d} + (\varepsilon_{S}^{1} - \varepsilon_{S}^{8}) t \qquad (1b)$$

: Fluid 1 and sample of
thickness t and static
dielectric constant $\frac{\varepsilon_{S}^{8}}{c_{S}^{5}}$,

$$C_{3} = \frac{\varepsilon_{S}^{2}}{d} \qquad (1c)$$

: Fluid of static dielectic
constant $\frac{\varepsilon_{S}^{2}}{c_{S}^{5}}$,

$$C_{4} = \frac{\varepsilon_{S}^{2}}{\varepsilon_{S}^{8}} \frac{\varepsilon_{S}^{8}}{d} + (\varepsilon_{S}^{2} - \varepsilon_{S}^{8}) t \qquad (1d)$$

: Fluid 2 and sample,

$$C_{5} = \frac{A}{d} \qquad (1e)$$

: Vacuum

using a fixed-electrode, parallel plate capacitor of area A and plate separation d. Combining the above equations, one arrives at the working equation:

$$\mathbf{s} = \frac{c_1 (1 + c_3/c_2 - c_3/c_1 - c_3/c_4)}{c_5 (c_1/c_2 - c_3/c_4)}.$$
 (2)

The significant feature of this approach is that the static dielectric constant of the sample is determined only from ratios of capacitances, the values of which can be known extremely well via three-terminal methods.

APPARATUS

The three-terminal capacitances were determined using an appropriately modified General Radio Type 1620-A capacitance measuring assembly. Details of the alterations are given elsewhere.^{10,11} The bridge was operated at 1000 Hz and 30 V.

An exploded view of the capacitance cell assembly is shown in Figure 1. An important feature is that there are four electrodes, an inner and an outer on each plate, which can be combined to give two separate threeterminal combinations. The inner and outer electrodes are separated by epoxy and 0.00025 in. mylar. The 0.002 in. thick mylar shims center both the sample insertion tool, which is free to move vertically upward to receive and discharge the sample, and the sample which is placed in the circular gap in the tool. The dimensions of the cell are such that for one inch diameter samples the condition that the fringing field effects be insignificant:

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Effective Guard Ring Width > 3 (3) Gap Width

is more than satisfied.

SAMPLES AND PROCEDURE

Samples of all three alkaline earth fluorides were obtained from both the Harshaw Chemical Co. and Optovac, Inc. in the form of one inch diameter disks. The preparation of the samples and the measurement procedure were the same as those given in our article on the static dielectric constants of some alkali halides.¹¹ The samples are 0.062 in. thick unless otherwise indicated. The raw data from a typical data run are listed in Table II.

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RESULTS AND DISCUSSION

The results for the 1000 Hz 300° K dielectric constants of various crystals of CaF₂, SrF₂, and BaF₂ are listed in Tables III-V respectively. The accuracy for an individual measurement is probably better than 0.01%.

Table III shows some interesting results. Note that the numbers for all Harshaw crystals, samples I-XIII are within 0.01% of each other. This includes two bi-crystals, samples IX and X, for one of which the grain boundary splits the crystal into two half-moons, and two thin crystals, samples XII and XIII. In addition the two 0.048 in. thick crystals had been purchased three years prior to the experiment, and stored in a desiccator during the interim. There is, however, grouping around the value 6.79845 and at 6.7988. This is thought to be a real difference due to trace impurities since the crystals came from two separate lab packs, and thus, possibly from two different boules.

The Optovac CaF₂ samples show both deviation from the Harshaw crystals and internal spread well beyond the uncertainty for an individual measurement. Clues to the apparent discrepancies are given by the dissipation factor.

The loss for all Harshaw-Simplex oil combinations is on the order of 25 ppm. The losses for Simplex oil and samples XIV, XV, XVI, XVIII, and XIX are 25, 50, 65, 110, and 150 ppm. respectively .. Thus, there is a direct a correlation between the loss and the low frequency dielectric constant. This implies that impurities or defects are responsible for the variations in $\frac{\varepsilon^{S}}{s}$. It is anticipated that experiments relating dielectric constant and loss to known impurity level content will soon be undertaken. It should be noted that accurate values of dissipation factor and conductance can be obtained from an analogous method of substitution. Sample XVII is a thin Optovac CaF, and was purchased three years prior to the experiment. Note that its dielectric constant fits into the spread nicely. The effects of polishing have been investigated previously, 11 and that there is no effect from our preparation process is confirmed by sample XVIII.

Samples I-IX of Table IV show that the Harshaw ^c SrF₂ crystals are not quite as uniform as the Harshaw CaF₂ in that the spread amounts to 0.03%. The 0.048 in. thick crystals, samples V and IX, fit into the spread of values confirming that there is no thickness effect. Also, there was a slight green tint evident in samples VIII and IX, but no anomalies were noted in the dielectric

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constant. The Optovac samples had a higher value of $\frac{e^{S}}{s}$ than did the Harshaw crystals, and, exhibited a correspondingly higher loss.

Samples I-VIII of Table V show that the static dielectric constants of the crystals of BaF₂ obtained from Harshaw were all within 0.01% of each other. The static dielectric constants and loss of the Optovac samples are again higher than for the Harshaw specimens. There was also a rather large difference between the two Optovac BaF₂ crystals, samples IX and X.

From Table I it is seen that only the work of Lowndes² and the numbers of Kaiser et al.⁵ obtained by geometrical methods agree with our values for all three crystals within quoted experimental uncertainties. Other work¹¹ has indicated that Lowndes has done about as well as is possible with the geometrical method. The numbers of Kaiser et al. overlap ours only because they quote large uncertainties.

Thus, the static dielectric constants of the alkaline earth fluorides have been determined very accurately and found not to vary monotonically with the atomic number of the cation. In addition, the value of c_s^S tends to be fairly sensitive to trace impurities, the quantitative investigation of which is soon to be undertaken. The pressure and temperature derivatives of the

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low frequency dielectric constants of these crystals are currently being studied to a high level of accuracy. Preliminary results for Harshaw CaF_2 and the uniformity of ε_s^s shown here for those crystals indicate the possibility of the use of CaF_2 as a pressure standard. The results from this investigation will be forthcoming shortly. Figure 1. Capacitance cell assembly: a, 0.002 in. thick mylar centering shims; b, sample insertion tool; c, guard ring; d, teflon FEP washers; e, aluminum guarded electrode; h, 0.00025 in. thick mylar film; i, 0.070 in. thick glass spacers.

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	This Work	Lowndes (1969) ^a	Jones (1967) ^b	Bosomworth (1966) ^C	Rao & Smakula (1965) ^d	Kaiser et al. (1962) ^e	Hojendahl (1935) ^f
Method	Method of Substitution	Geom.	Geom.	Curve fit dispersion relation	Geom.	Geometrical curve fit Kramers - Kronig	Mixed - Liquid
Temp.	300°K	300° K	300° K	300° K	300°K	300° K	
CoE	Harshaw 6.7984 -6.7988	6 91	6 75	6 6 7	6 79	6.7	9 42
CaF ₂	Optovac 6.8074- 6.8432		6.35	. 0.03	0.78	6.65	0.43
S #E	Harshaw 6.4647- 6.4664	6.50		6 20	6.48	6.6	7.69
Srr ₂	Optovac 6.4700- 6.4703			•••••		6.14	
BaF ₂	Harshaw 7.3590- 7.3595 *	7.32	7.02	6,94	7.28	7.2	7.33
	Optovac 7,3606- 7,3630					6.73	

TABLE I: Comparison of literature values for the static dielectric constants of the alkaline earth fluorides.

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TABLE I; - Continued

genetica (1.186) € - Norman 48	This Work	Lowndes (1969) ^a	Jones (1967) ^b	Bosomworth (1966) ^C	Rao & Smakula (1965) ^d	Kaiser et al. (1962) ^e	Hojendahl (1935) ^f
Quoted Error	.01%	.5%	1%	1%	.5%	5%	

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	BRASS	CELL	ALUMINUM CELL		
	Normal	Reverse	Normal	Reverse	
с ₁	.891016 .891016	.892550 .892553	.887718 .887720	.898471 .898478	
C ₂ (flip) (flip)	2.324319 2.324279 2.324328 2.324308	2.328436 2.328473 2.328400 2.328515	2.302438 2.302507 2.302461 2.302428	2.330274 2.330223 2.330205 2.330254	
C ₃	1.899940 1.900005	1.903213 1.903278	1.893005 1.893050	1.915937 1.915986	
C ₄ (flip) (flip)	2.677185 2.677181 2.677205 2.677206	2.681821 2.681844 2.681867 2.681845	2.663385 2.663367 2.663370 2.663385	2.695613 2.695631 2.695639 2.695602	
C ₅	.4114719	.4121805	. 4099437	. 4149131	
ε ^S s	6.798852	6.798842	6.798831	6.798826	

TABLE II:- Raw data for sample I of Table III. The capacitances are in picofarads. Fluid 1 is Simplex projector oil and fluid 2 is castor oil.

Sample	Source and Comments	Measuring group	ε ^s s
I	H ·	12	6.7988
II	H	12	6.7988
III	н	12	6.7985
IV	Н	11	6.7984
V .	H s	11	6.7984
VI	Н	11	6.7985
VII	H .	11	6.7988
VIII	H .	11	6.7984
IX	H-(Bi-crystal)	8	6.7985
x	H-(Bi-crystal)	15	6.7988
XI	Н	16	6.7985
XII	H(.048 "old")	_ 15	6.7986
XIII	H(.048 "old")	13	6.7986
XIV	0	13	6.8074
XV	0	13	6.8077
XVI	0	14	6.8123
XVII	0(.048."old")	15	6.8291
XVIII	O(Bi-crystal)	6	6.8343
XVIII	Repolished	8	6.8344
XIX	0	13	6.8432

TABLE III. The 300°K 1000Hz dielectric constants of some CaF₂ crystals.

Sample	Source and Comments	Measuring group	ε ^S s
I	Н	8	6.4648
II	H	12	6.4650
III	Н	12	6.4664
IV	Н	12	6.4651
V	H(.048")	13	6.4648
VI	H .	14	6.4647
VII	н	14	6.4650
VIII	H (green tint)	14	6.4652
IX	H(.048") (green tint)	15	6.4653
X	0	8	6.4703
XI	0	15	6.4700
	1		1

TABLE IV:- The 1000 Hz 300°K dielectric constants of some samples of SrF₂.

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Sample	Source and Comments	Measuring group	es s
· I.	Н	13	7.3591
II	Н	13	7.3591
III	Н	14	7.3593
IV	Н	14	7.3591
v	н	14	7.3594
VI	н	15	7.3590
VII	Н	15	7.3590
VIII	H.	16	7.3595
IX	ο .	8	7.3630
X	o .	12	7.3606

TABLE V:- The 1000Hz 300°K dielectric constants of some crystals of BaF₂.

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